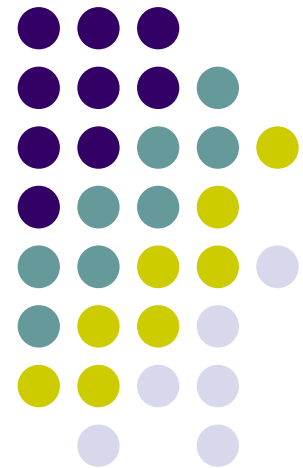


FPCCD Vertex Detector R&D for ILC

Yasuhiro Sugimoto
KEK
@Vertex Detector Review





Collaboration

- KEK
 - A. Miyamoto, K. Nakayoshi, Y. Sugimoto
- JAXA/ISAS
 - H. Ikeda
- Tohoku University
 - T. Nagamine, Y. Takubo, H. Yamamoto
- Tohoku Gakuin University
 - K. Abe



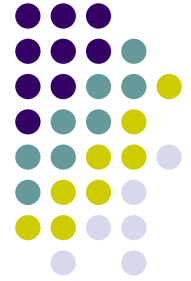
Basic concept (1)

- Pair background at small R
 - ~5000 hits/cm²/train with B=3T and R=20mm (GLD)
 - Pixel occupancy ~10% for 25μm pixel (several pixels are fired for one track hit) if signal is accumulated for one train
 - In order to keep the occupancy small (<1%),
 - read out 20 times per train (1ms), or
 - 20 times finer pixel → Fine Pixel CCD (FPCCD)
- is necessary



Basic concept (2)

- FPCCD Vertex detector
 - Fine pixel of $\sim 5\mu\text{m}$ (x20 more pixels than “standard” pixels) to keep low pixel occupancy
 - Fully depleted epitaxial layer to minimize the number of hit pixels due to charge spread by diffusion
 - Accumulate hit signals for one train (2625 BX) and read out between trains (200 ms) → No power cycling
 - Low temperature ($\sim 220\text{ K}$) operation to reduce dark current and to increase radiation tolerance



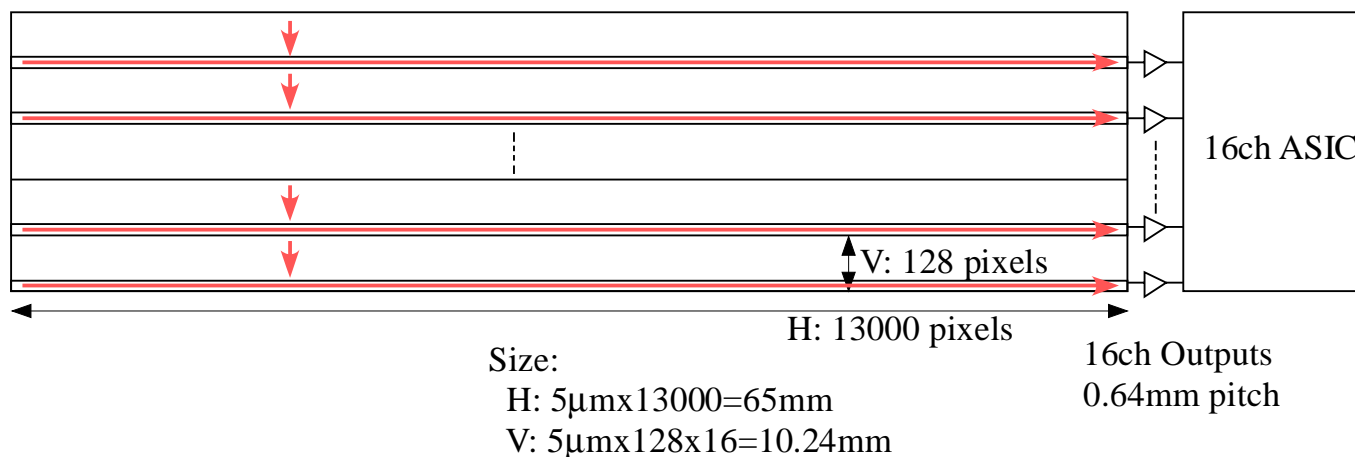
Advantages of FPCCD VTX

- Completely free from beam-induced RF noise (EMI)
- Excellent spatial resolution of $\sigma_x \sim 1.4\mu\text{m}$ even with digital readout
- Excellent two-track separation capability because of fine pixels and fully depleted epitaxial layer
- Capability of low-energy pair-background rejection by making use of hit-cluster shape
- Simple structure which enables large wafer size with high yield rate
- No heat source in the image area
- No need for very high readout speed



Schematic design (1)

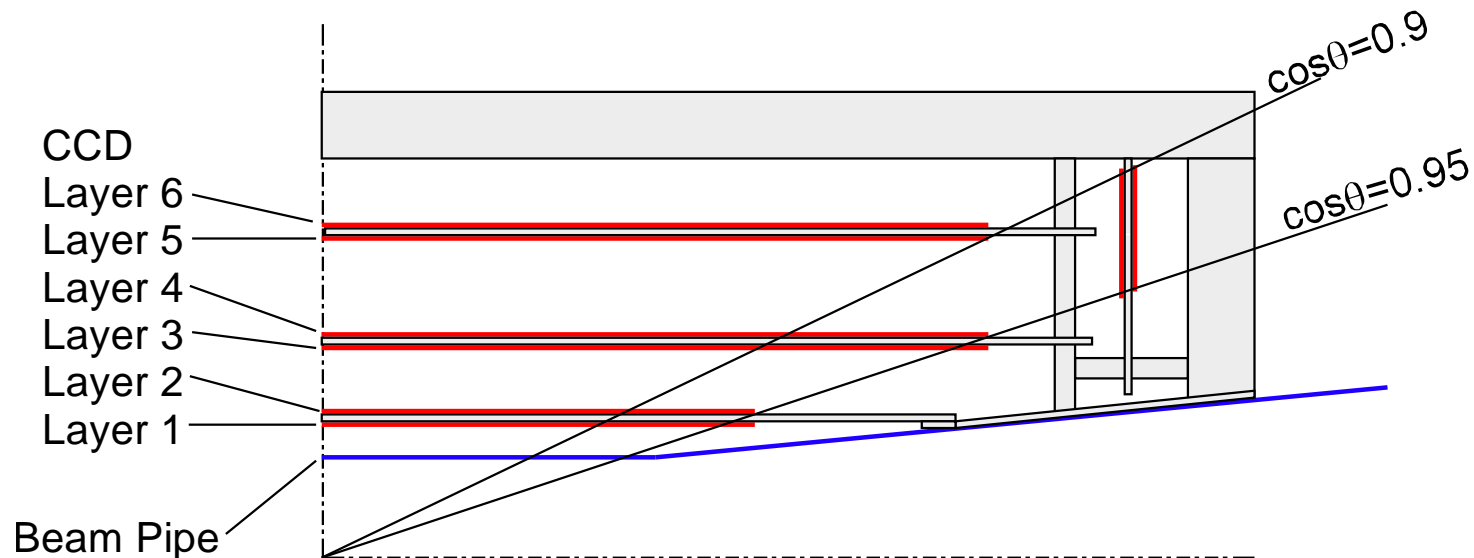
- Sensor and ASIC (for 3T detector – GLD)
 - $\sim 5\mu\text{m}$ square pixel
 - 128(V)x13000(H) pixels/ch for inner layers
 - 128(V)x20000(H) pixels/ch for outer layers
 - 16ch/wafer for inner layers and 32ch/wafer for outer layers
 - $10 \times 65\text{mm}^2$ for inner layer and $20 \times 100\text{mm}^2$ for outer layers
 - 15 – 20 μm thick fully depleted epitaxial layer
 - Readout speed $\sim 10\text{Mpixels/s}$



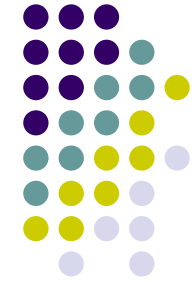


Schematic design (2)

- Vertex detector
 - Two CCD layers make a ladder
 - 3 ladders make the vertex detector
 - Operation at ~ 220 K
 - Ladders are confined in a cryostat
 - Angular coverage:
 - $|\cos\theta| < 0.9$ with all barrel part
 - $0.9 < |\cos\theta| < 0.95$ with barrel and forward disk



Schematic design (3)

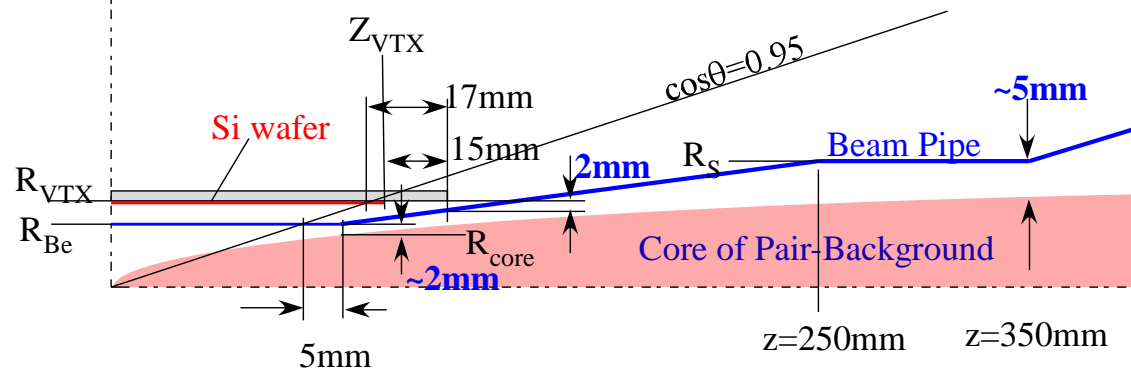
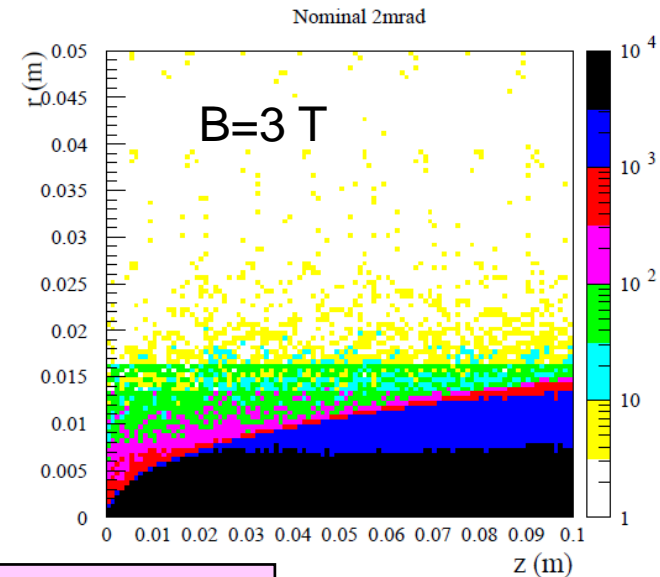


- VTX inner radius
 - Design criteria:
Beam pipe should not be hit by dense core of the pair background

E_{CM}	Option	R_{bp}	R_{VTX}
500 GeV	Nominal	13 mm	17 mm
1 TeV	High L A1	15 mm	20 mm
500 GeV	High Lum	19 mm	24 mm

For 3T detector

Strong dependence on machine parameters





Expected performance (1)

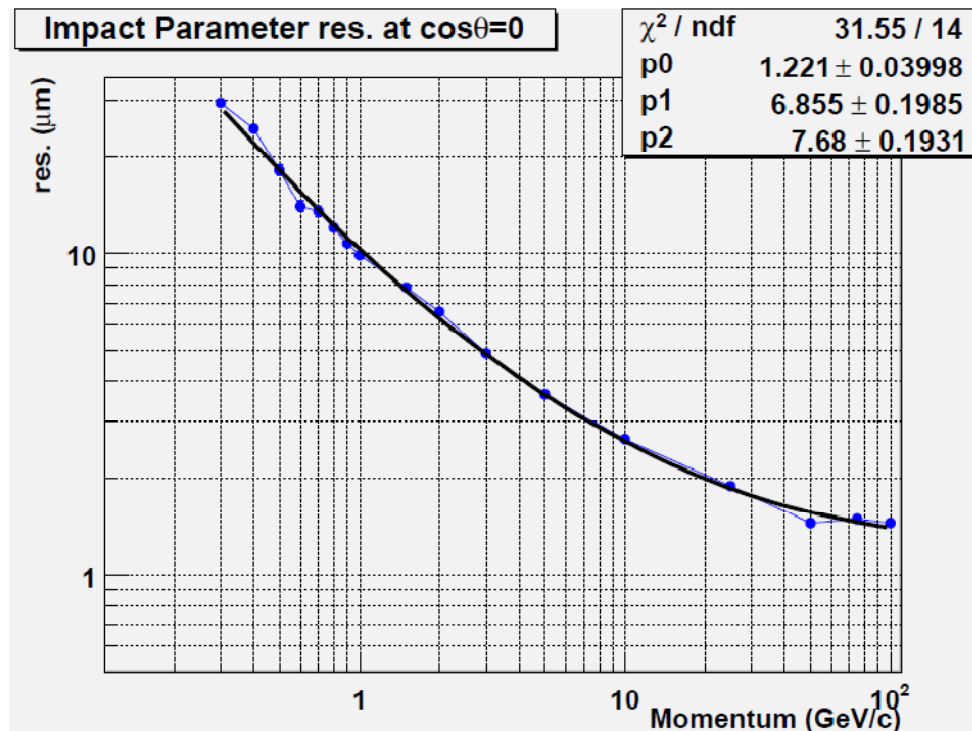
- Simulation model
 - 6 layers of CCD cylinders
 - R=20, 22, 32, 34, 48, 50 mm
 - Beam pipe: R=18mm, t=250 μ m Be
 - Each layer has 80 μ m thickness and no ladder material
 - 3T magnetic field
 - GEANT4 based simulator “JUPITER”



Expected performance (2)

- Impact parameter resolution

- The result is well fitted with $\sigma = \sigma_0 \oplus \frac{\sigma_1}{p} \oplus \frac{\sigma_2}{p^2}$ rather than $\sigma = \sigma_0 \oplus \frac{\sigma_1}{p}$



Performance goal of

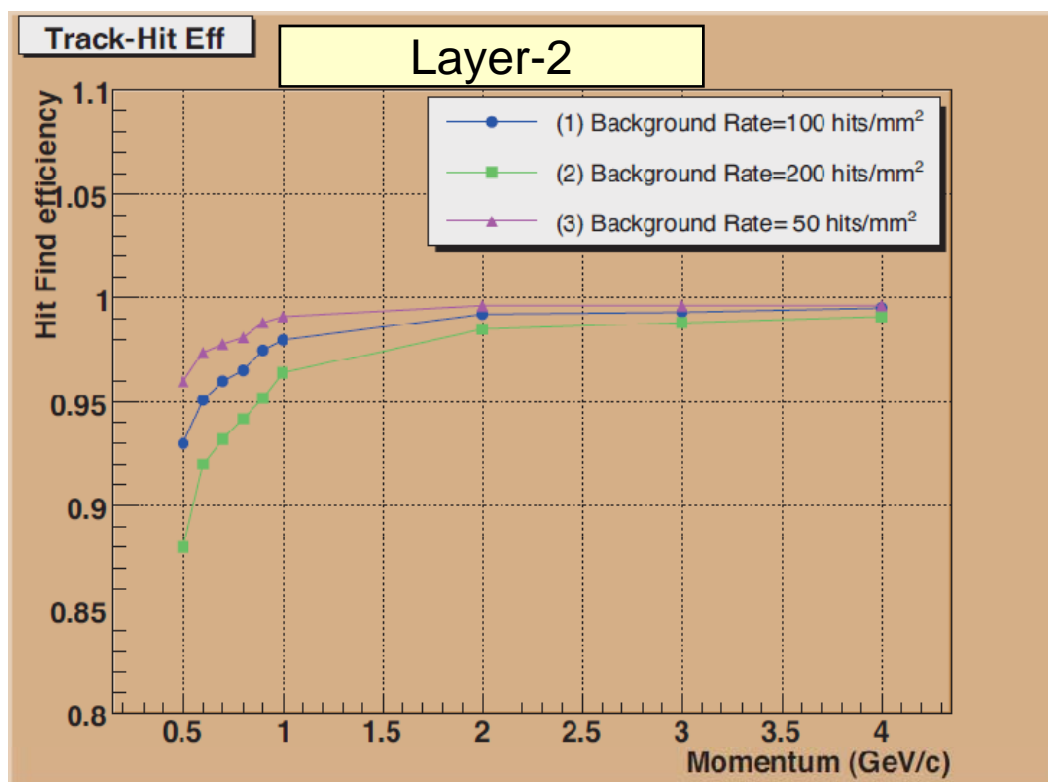
$$\sigma = 5 \oplus \frac{10}{p} \mu\text{m}$$

is satisfied



Expected performance (3)

- Track-hit matching efficiency
 - Efficiency of finding the correct hit in the inner layer by extrapolating a track from outer layers in the presence of background hits



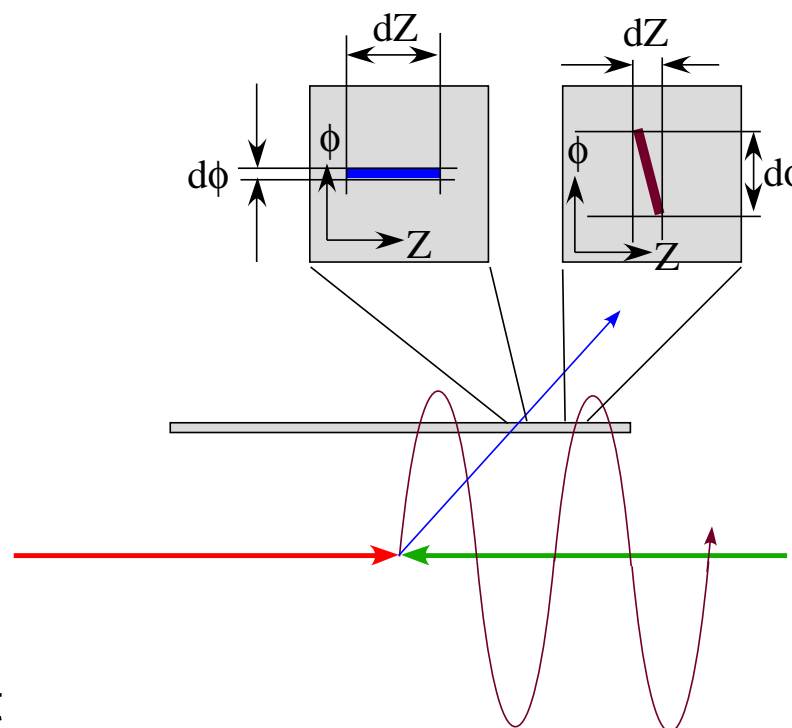
- Improvement is expected by
 - taking correlation of hit points on layer-1 and layer-2 into account (making “mini-vector”)
 - background rejection using hit cluster shape

Further study is necessary

Background rejection



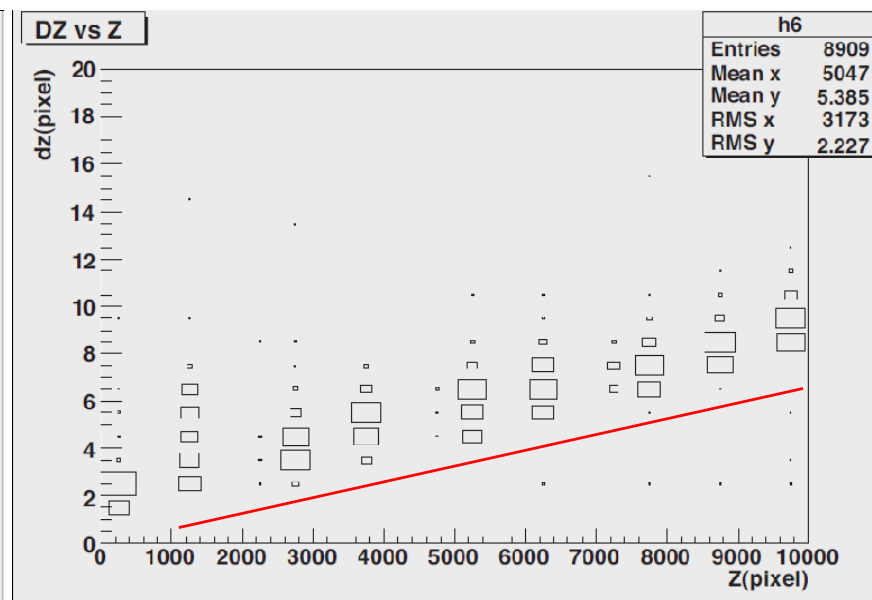
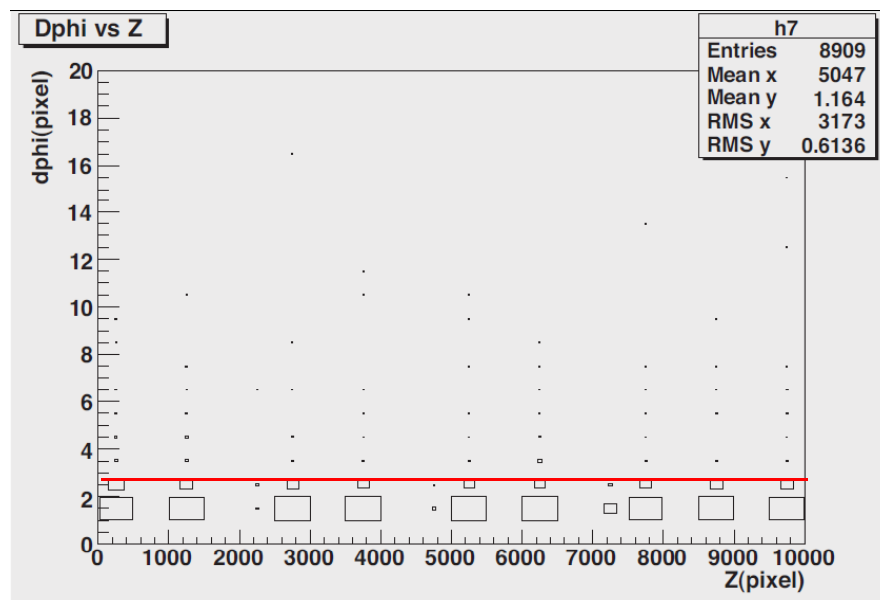
- Background rejection by cluster shape
 - FPCCD has the pixel size smaller than the thickness of the sensitive layer
 - ➔ Rough measurement of incident angle can be done with single layer using the cluster shape
 - Pair-background particles have typical momenta of few tens of MeV/c and curvature of few cm, and incident direction is different from that of high p_t particles associated with physics events



Simulation for B.G. rejection(1)



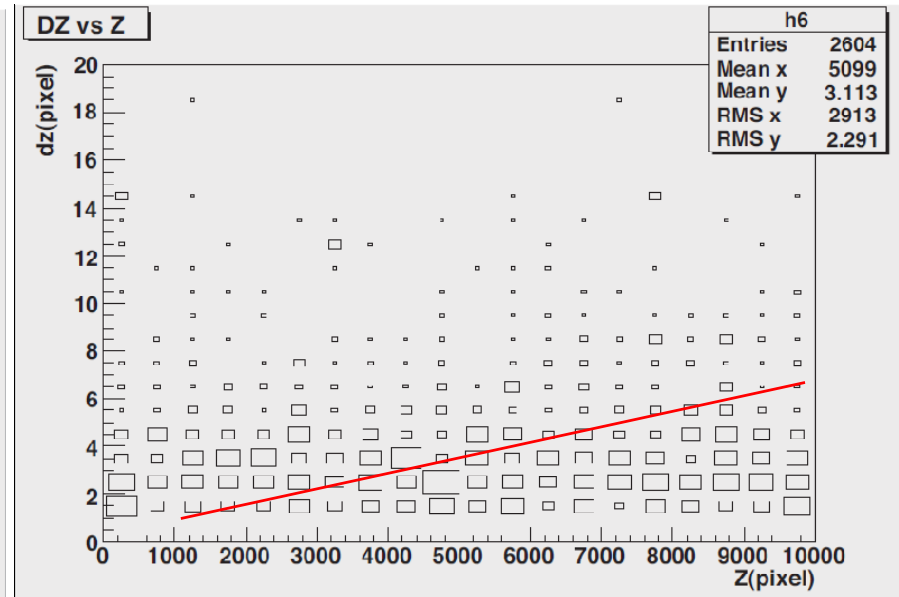
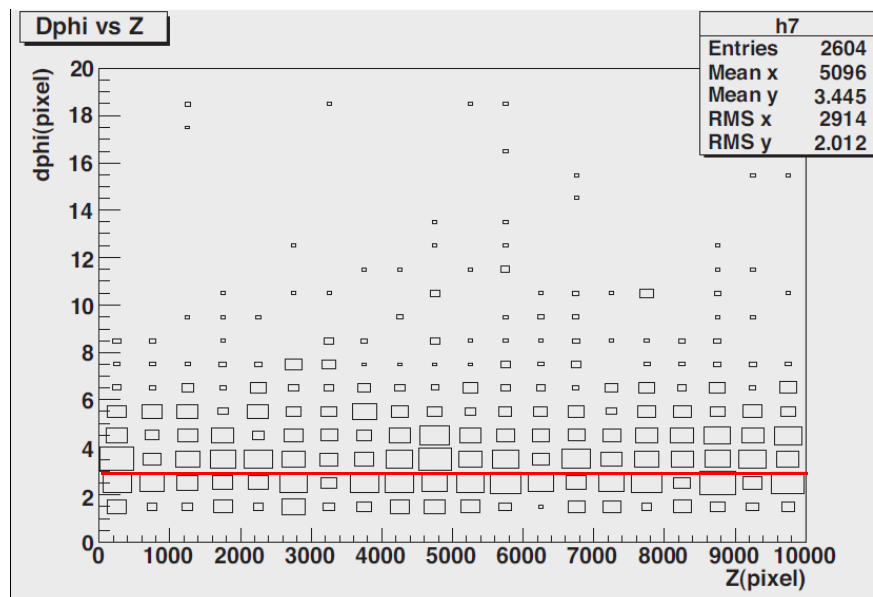
- 1 GeV/c muon



Simulation for B.G. rejection(2)



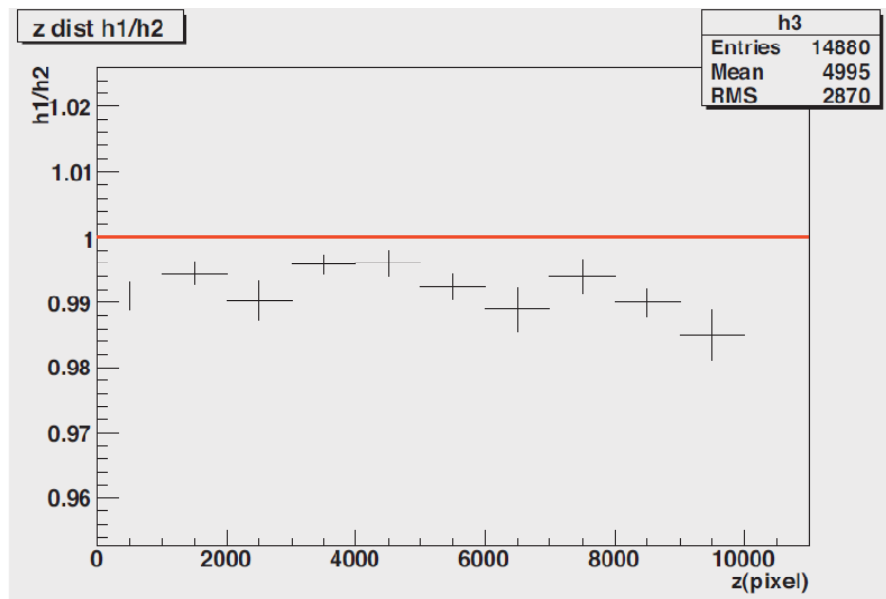
- Pair-background particles



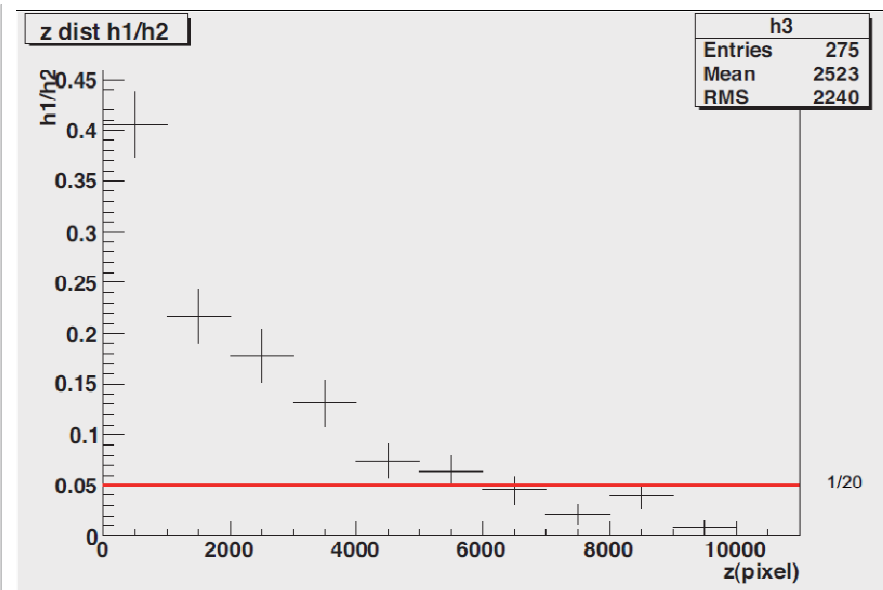
Simulation for B.G. rejection(3)



- Rejection performance



For 1 GeV/c muons



For pair b.g. particles



R&D issues (1)

- Sensor R&D
 - Fully depleted CCD
 - Prototype FPCCD
 - Small size ($\sim 10\text{mm}^2$) for proof of principle by 2010
 - Full size ($10 \times 65\text{mm}^2$ and $20 \times 100\text{mm}^2$) by 2012 – 2013
 - Key issues:
 - Output circuit – Low power consumption, high speed, low noise
 - Radiation tolerance



R&D issues (3)

- Engineering issues
 - Low material structure is extremely important
 - Wafer thinning
 - Design of ladders
 - Design of support structure of ladders
 - Cryostat and cooling system
 - Other issues
 - Integration to detector system
 - Alignment
 - Timeline
 - Design of FPCCD vertex detector by 2010
 - Full-scale engineering prototype by 2012 – 2013 for the construction-ready EDR



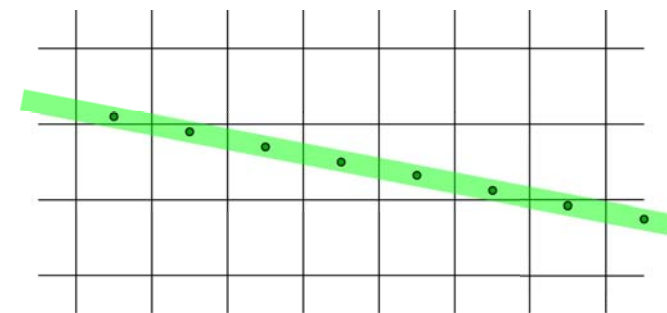
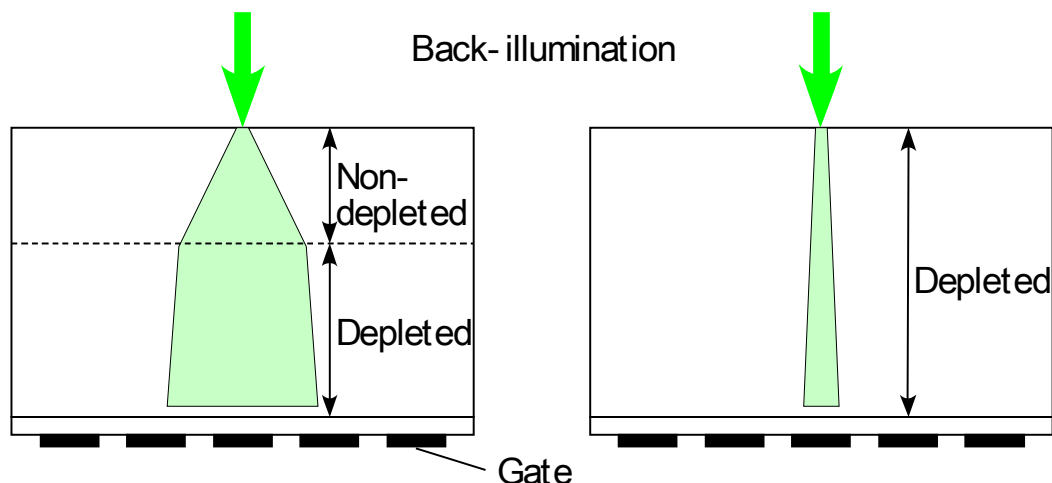
R&D status

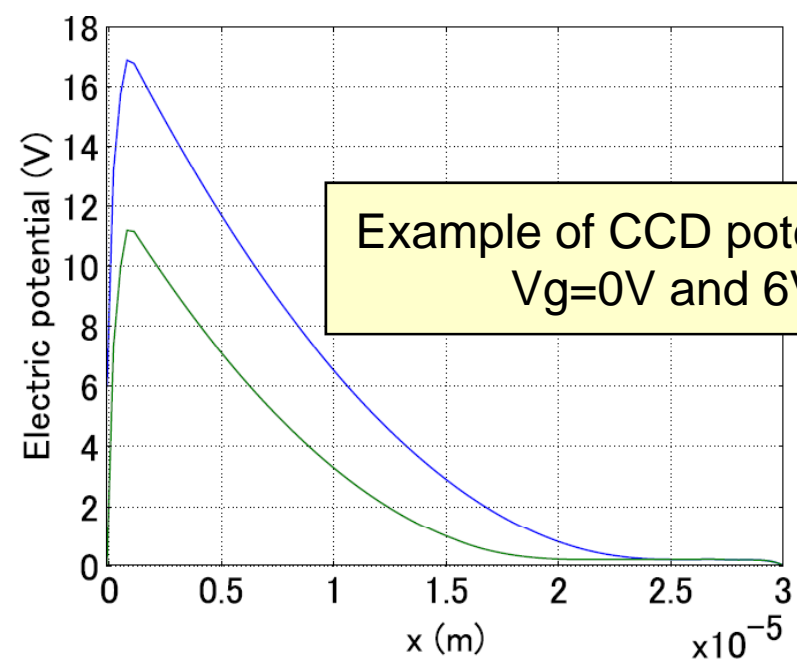
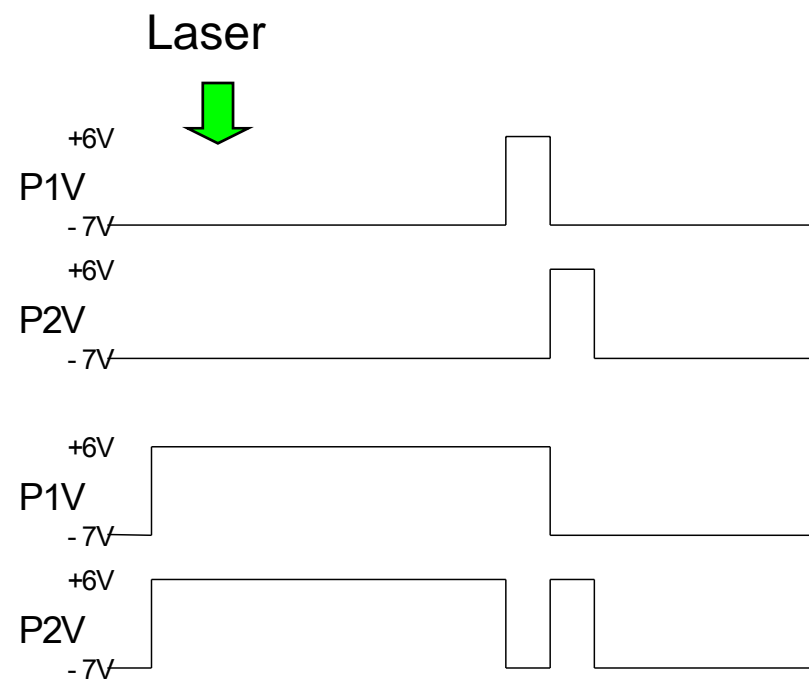
- Development of fully depleted CCDs
- Design of the first prototype of FPCCD
- Design of readout ASIC



Fully depleted CCD (1)

- Several samples are obtained from Hamamatsu
- Confirmation of full-depletion by measurement of charge spread
 - LASER light (532nm) focused to a thin (<pixel size) line was illuminated to back-illuminating CCDs slightly inclined w.r.t. CCD pixel grid → Effectively scan inside a pixel
 - Compare signal distribution between $V_{\text{gate}} = -7\text{V}$ and $V_{\text{gate}} = +6\text{V}$ during LASER illumination
 - If distributions are same, the CCD is fully depleted in both cases



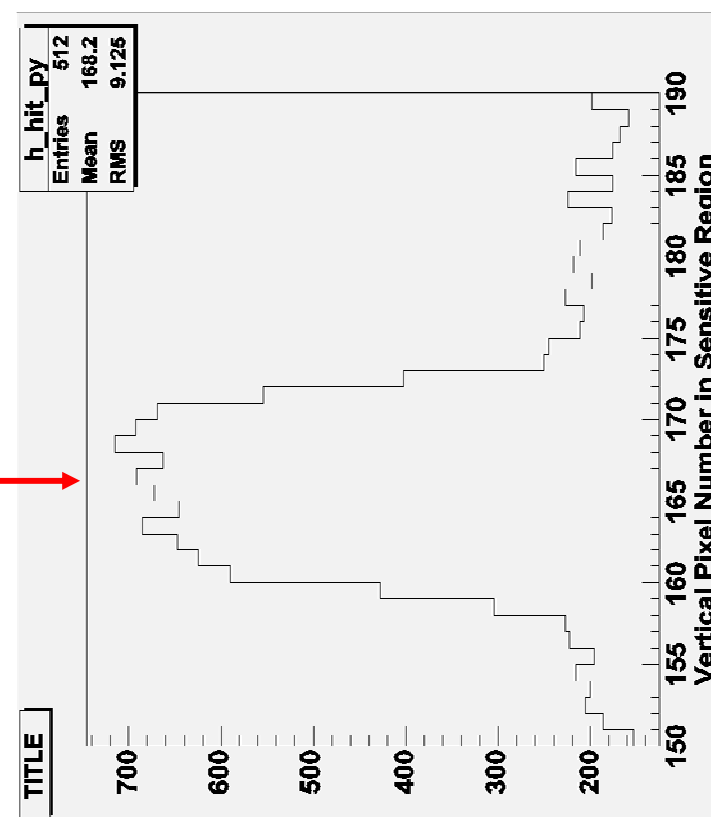
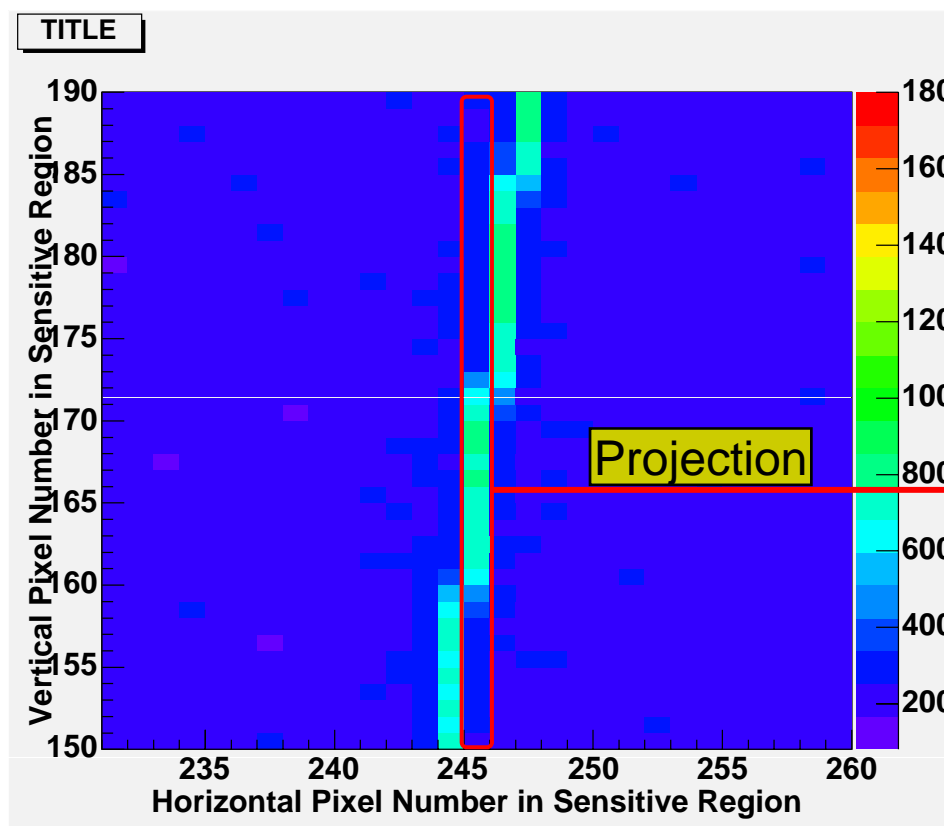


Example of CCD potential for $V_g=0V$ and $6V$



Fully depleted CCD (2)

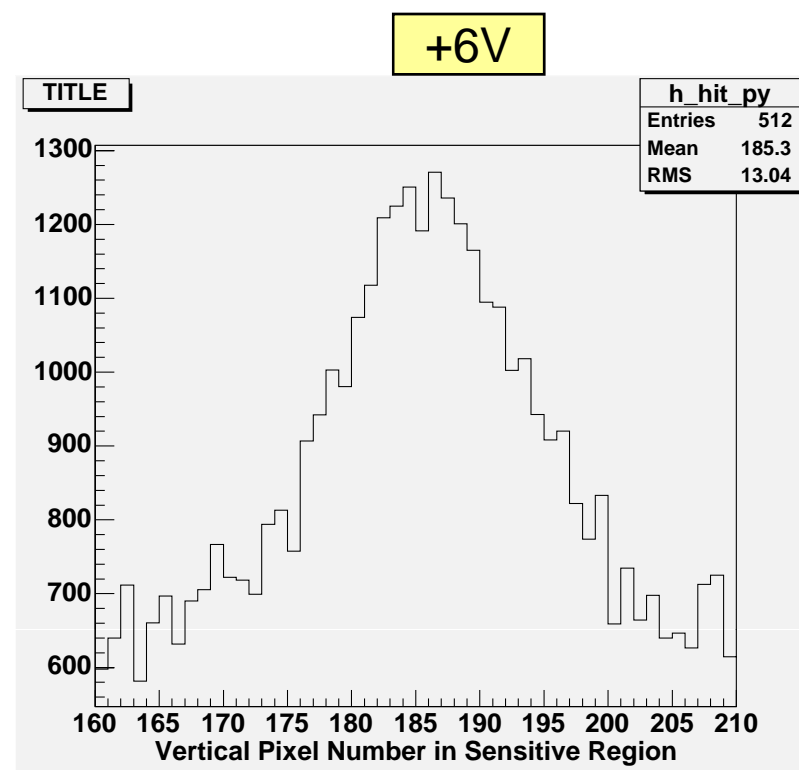
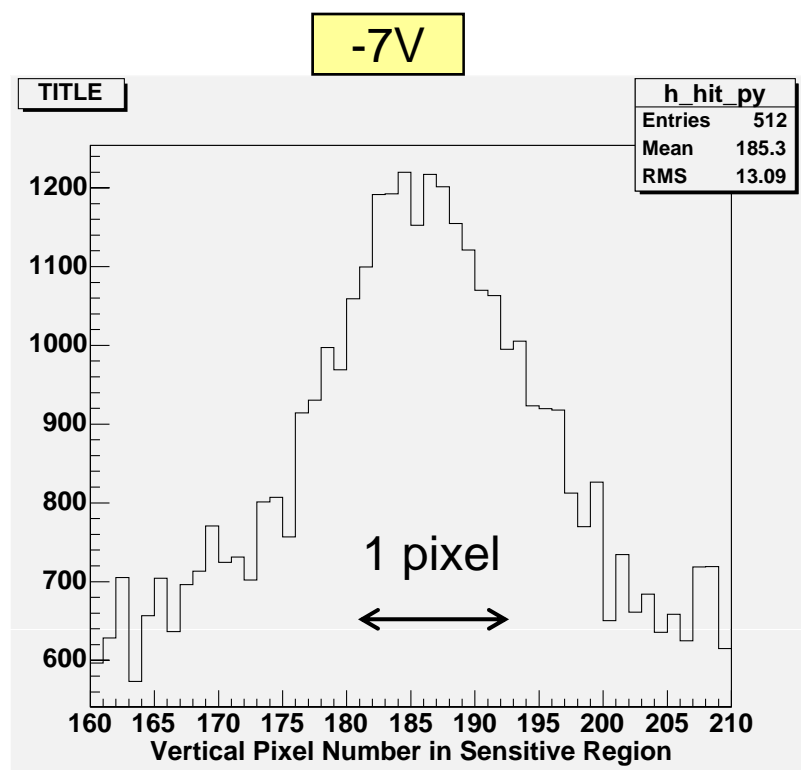
- Results of experiments





Fully depleted CCD (3)

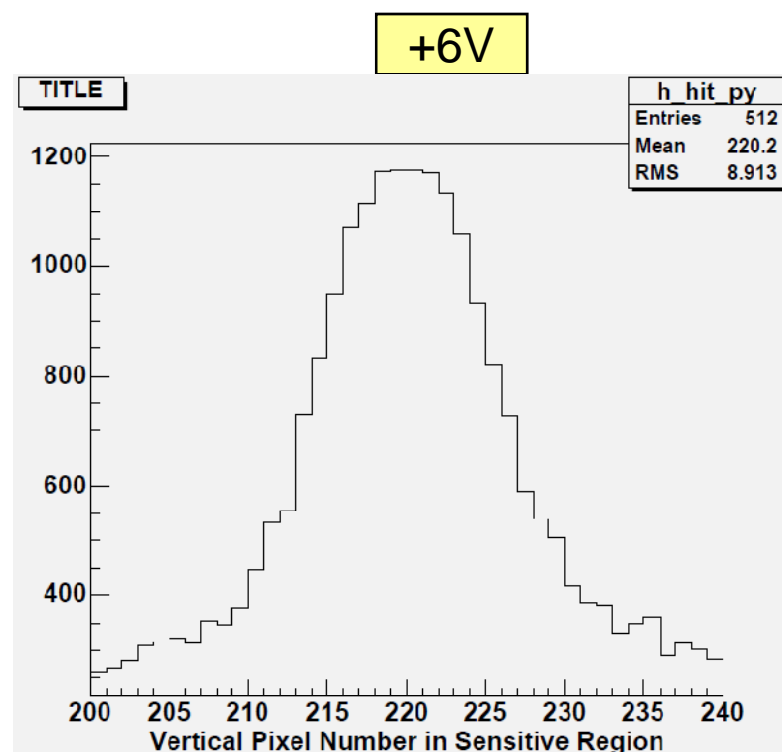
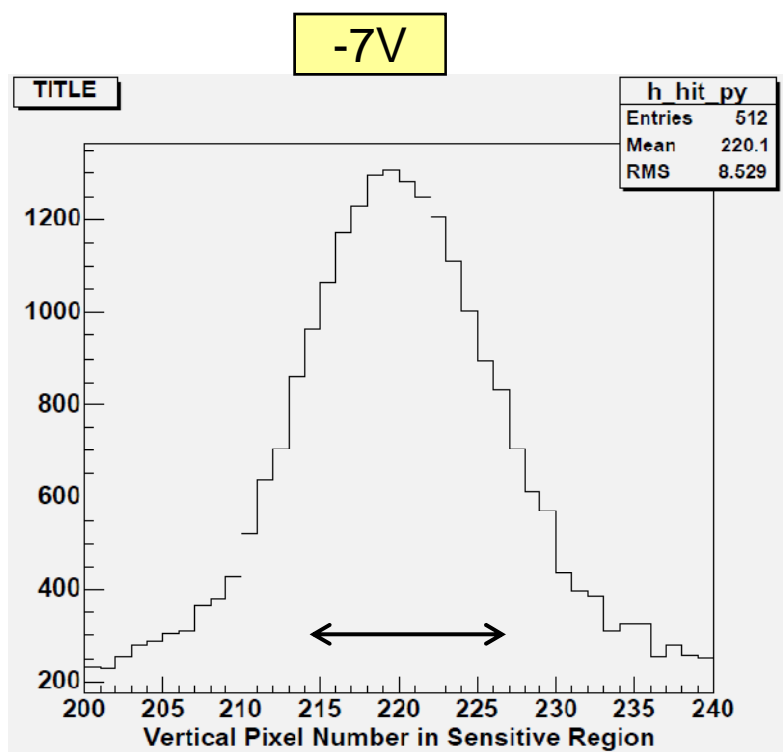
- S7170 Standard
 - Low resistivity epitaxial layer → thin depletion layer





Fully depleted CCD (4)

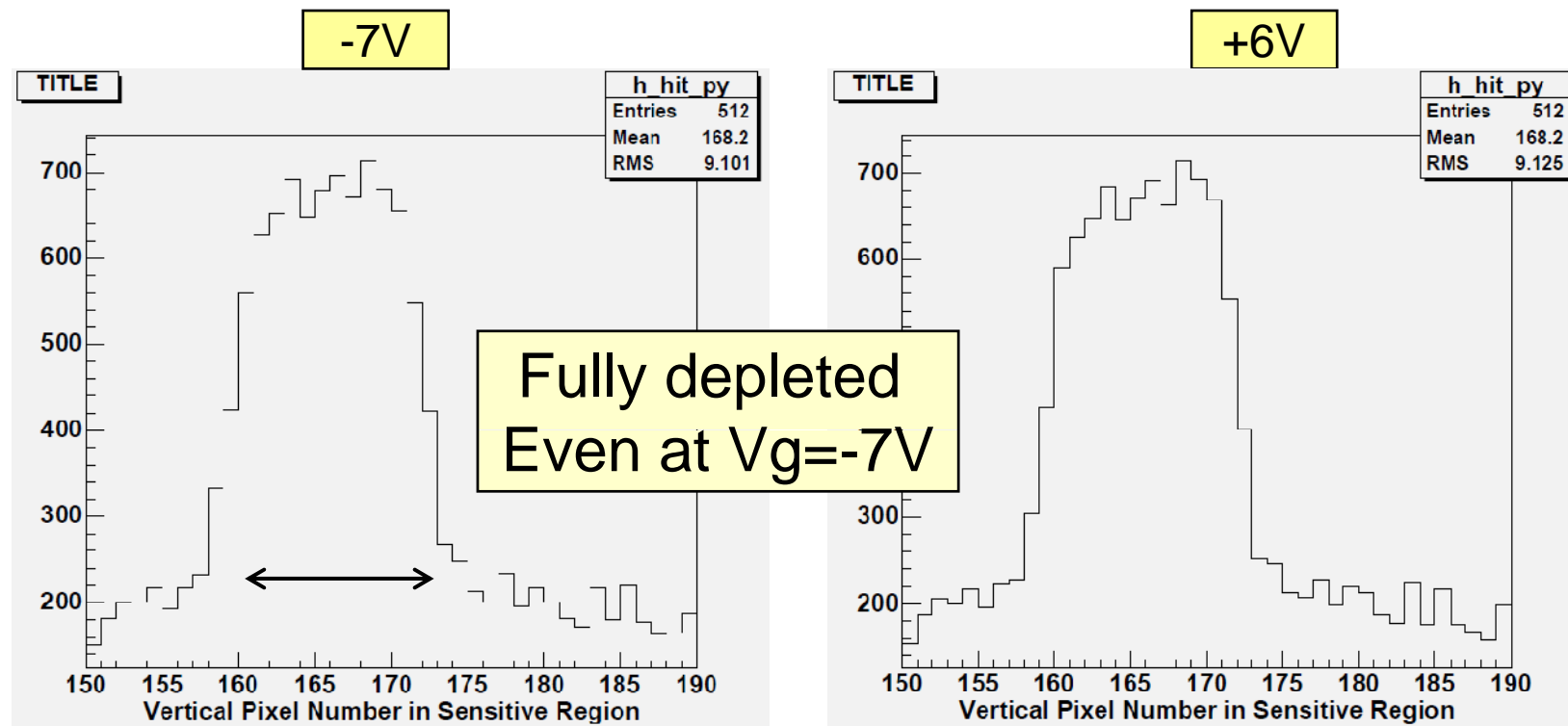
- S7170 Deep2
 - Higher resistivity 30 μm thick epitaxial layer





Fully depleted CCD (5)

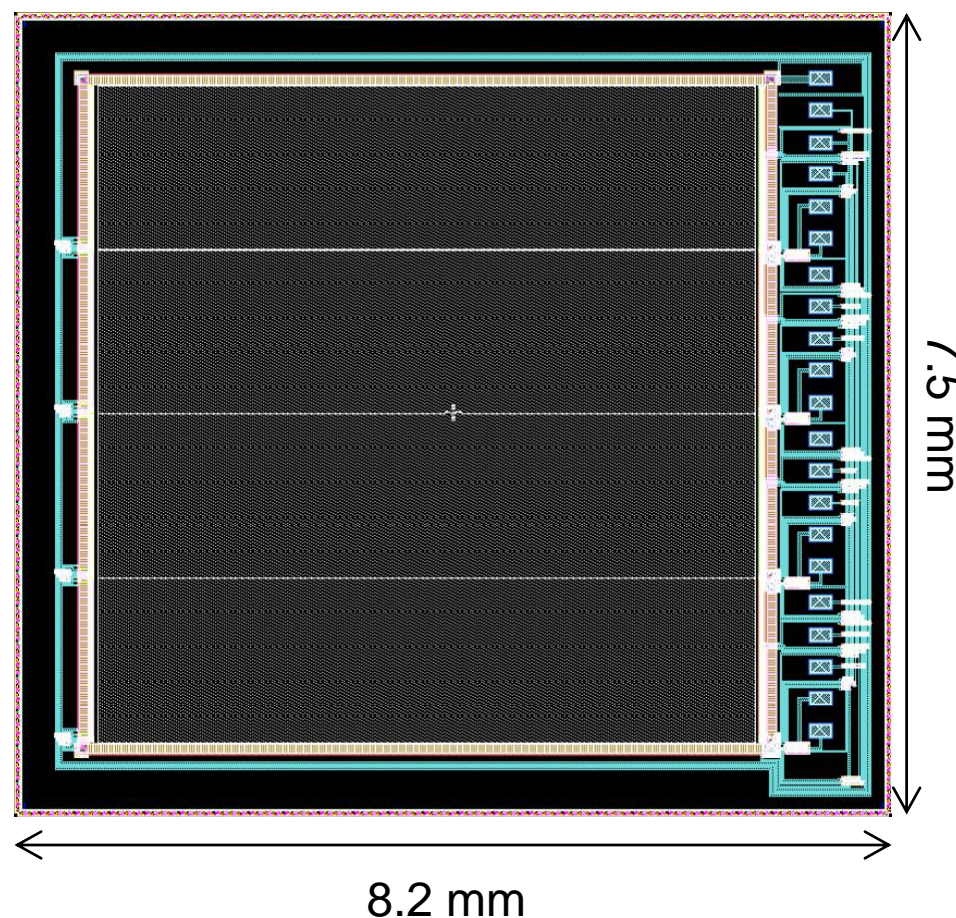
- S7170 SPL24mm
 - Highest resistivity 24 μ m thick epi-layer





Design of prototype FPCCD

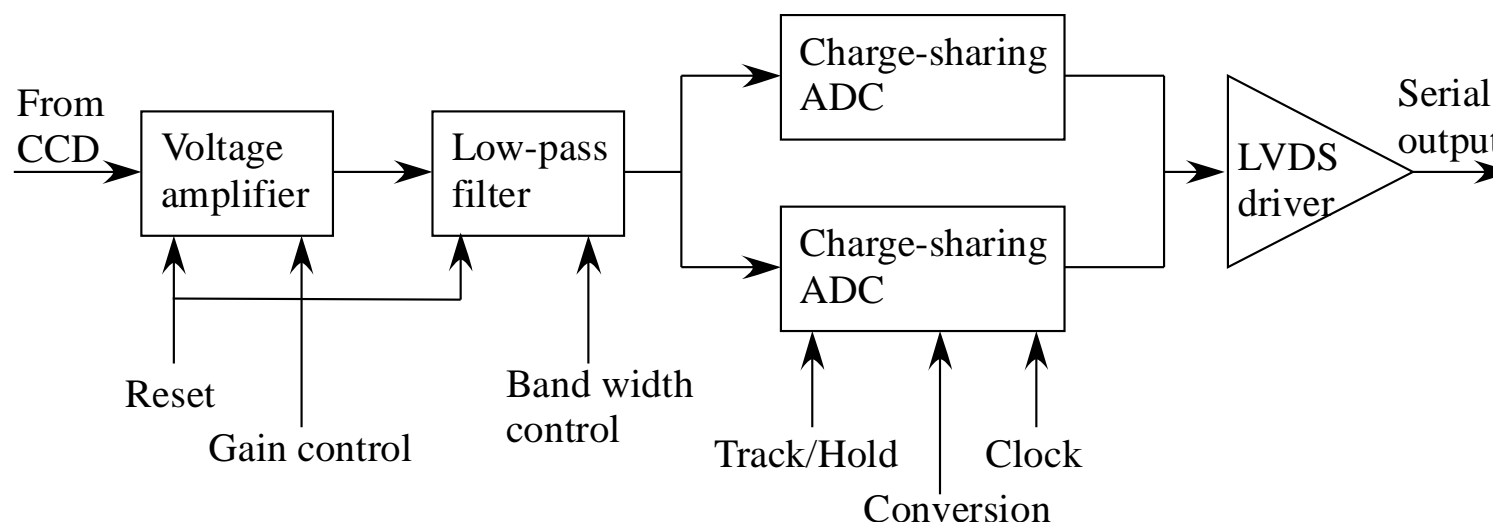
- 12 μ m pixel size
- 24 μ m epitaxial layer
- 512x512 pixels
- 6.1mm² image area
- 4ch /chip
- 128(V)x512(H) pixels for each channel
- 4 different design of output amp
- To be delivered at the end of 2007



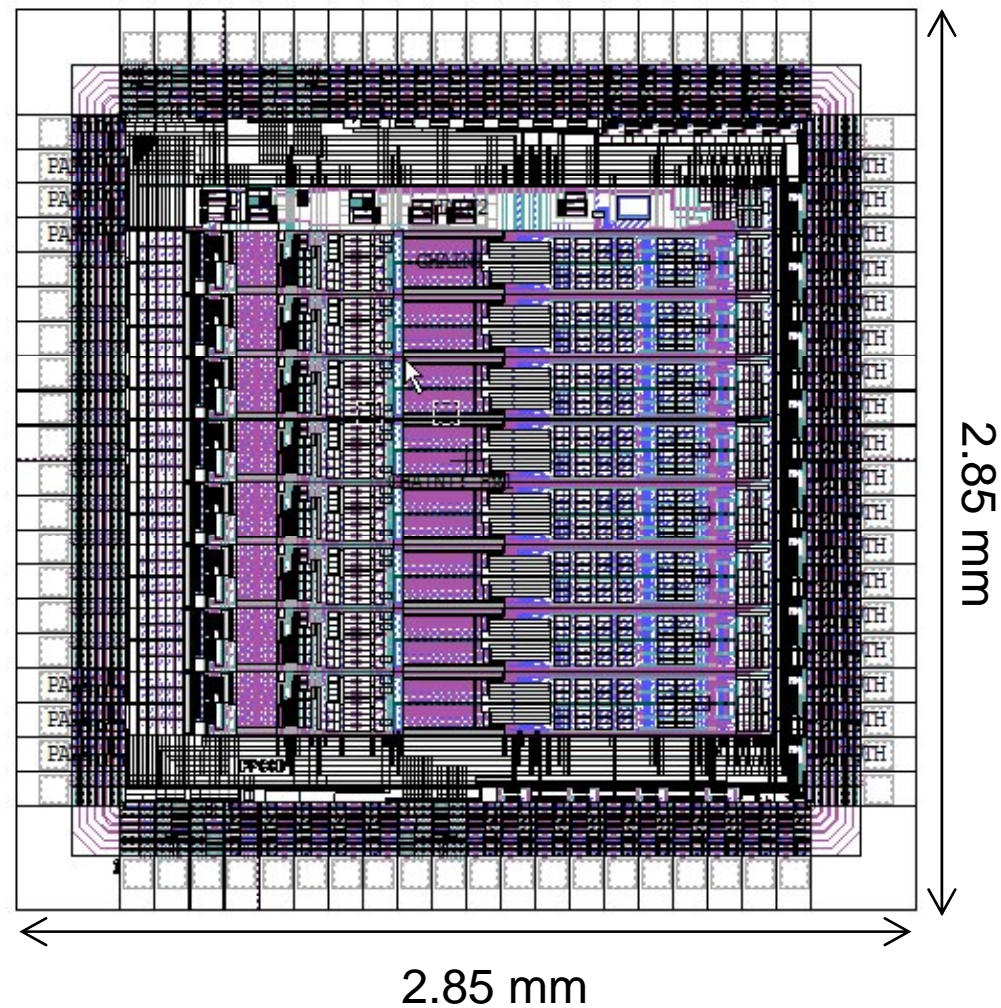


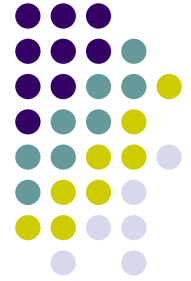
Design of readout ASIC (1)

- Amp, LPF, CDS, ADC, and LVDS driver
- 8 ch/chip
- Two ADCs/ch work alternatively to achieve fast readout
- Max sampling rate ~ 10 Msample/s
- Charge sharing SAR ADC → Low power
- 0.35μm CMOS
- To be delivered at the end of 2007



Design of readout ASIC (2)





Summary and outlook (1)

- R&D for FPCCD vertex detector has just begun in 2006 supported by JSPS funding
- So far, we have made simulation studies and obtained promising results on
 - Impact parameter resolution
 - Background rejection using hit-cluster shape
- Concerning the sensor R&D, we have developed fully depleted CCDs in collaboration with HPK, and started design of a prototype FPCCD
- A prototype of front-end ASIC is designed and submitted to a foundry
- In order to make a construction-ready design of the FPCCD vertex detector, we think we need
 - At least 6 times iteration of production-characterization cycle of FPCCD and front-end ASIC
 - R&D of peripheral circuits and DAQ system
 - Engineering study including full-scale prototype
- But, established support is far below the need to complete these tasks

Summary and outlook (2)



- If we succeed to obtain necessary support in future, we plan to
 - Demonstrate the feasibility of FPCCD vertex detector by making small prototype of FPCCD and front-end ASIC by 2010
 - Study on key technologies of engineering issue such as wafer thinning, ladder design, and cooling system
 - Carry out beam tests of small prototype in ~2010
 - Develop full-size prototype sensors, total readout system, and full-size engineering prototype detector for construction-ready EDR by 2012 – 2013